

# Application of a microscopic model to efficiency droop of InGaN LEDs

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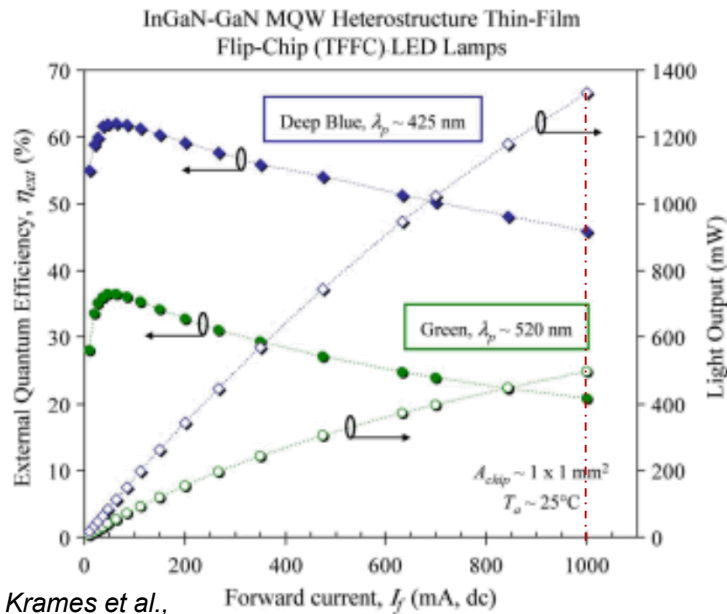
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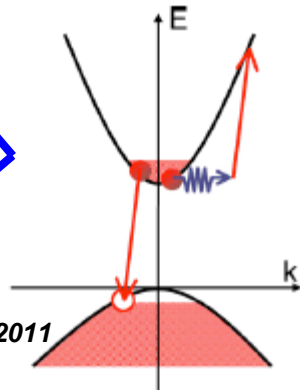
# Motivation: High Efficiency InGaN LEDs for Solid State Lighting



Krames et al.,  
*J. Displ. Technol.* (2007)

## Indirect Auger recombination

potential  
non-radiative  
mechanisms



Kioupakis et al, APL, 2011

## Primary Efficiency Limitations

- High operating currents ( “efficiency droop” )
- High operating temperatures
- Longer wavelengths ( e.g., green and longer )

Recombination model:

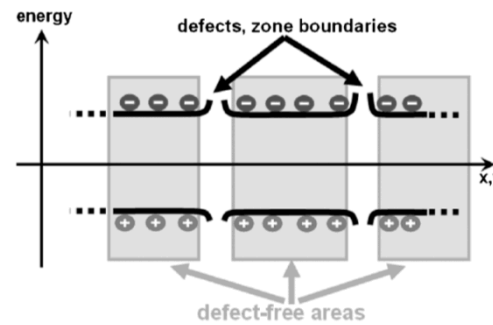
$$\varepsilon_{IQE} = \frac{Bn^2}{An + Bn^2 + Cn^3 + Dn^m + \dots}$$

Shockley-Read-Hall  
(nonrad at defects)

Radiative

Auger and higher  
order processes

## Carrier delocalization/ defect recombination



Hader et al, APL 2010

## Carrier capture / leakage

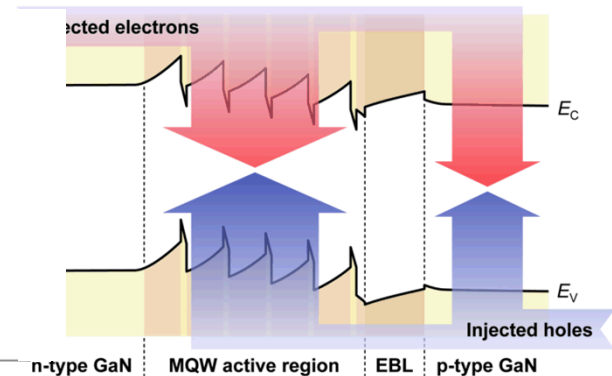


Figure: E. F. Schubert

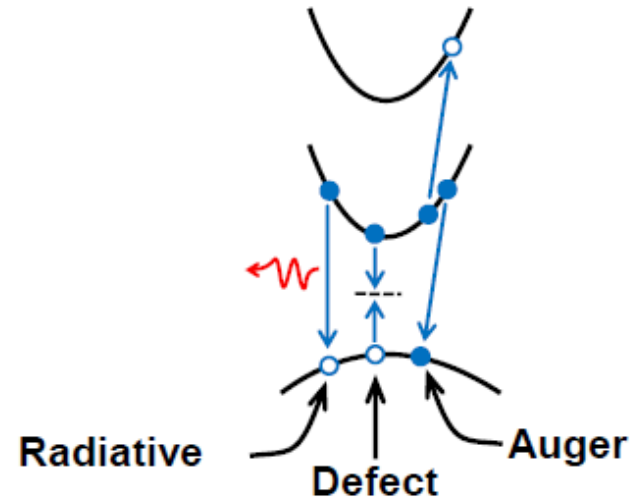
# I. Application of a Microscopic Model to Study Efficiency Limitations in InGaN LEDs

## LED rate-equation model (“ABC”)

$$\frac{dN}{dt} = \frac{J}{ed} - \underset{\substack{\uparrow \\ \text{Defects}}}{AN} - \underset{\substack{\uparrow \\ \text{Spontaneous} \\ \text{emission}}}{BN^2} - \underset{\substack{\uparrow \\ \text{Auger?}}}{CN^3}$$

$$\text{Internal quantum efficiency} = \frac{BN^2}{AN + BN^2 + CN^3}$$

## Radiative and Non-radiative Processes



## Model Shortcomings:

- a) True density dependence not simple  $N^m$
- b) Carrier capture/leakage ignored
- c) Plasma heating and other non-equilibrium effects ignored

## Approach:

- Advance rate equation model:
  - *microscopic radiative component*
  - *non-equilibrium effects*
- Explore non-linear contributions of defect-related recombination

# Model Approach

“ABC” Quasi equilibrium model  
(phenomenological rate equations)

k-resolved, relaxation rate  
approx.

k-resolved, quantum  
kinetic theory

## Key Advances from “ABC” model



→ Replace total “N” with k-resolved distributions  
→ bandstructure implemented directly into model

$$N = \sum_k n_{e(h),k}$$

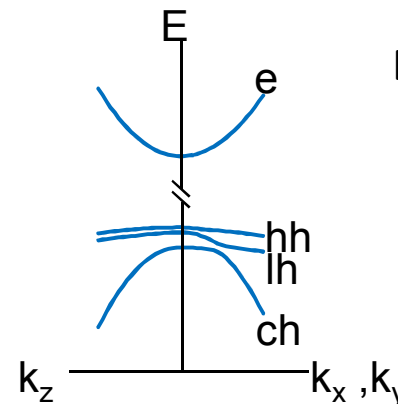
→ Track carrier distributions in both QWs and barriers  
→ treatment of carrier injection and leakage

→ Carrier-carrier and carrier-phonon interactions  
→ Relaxation rate approximation

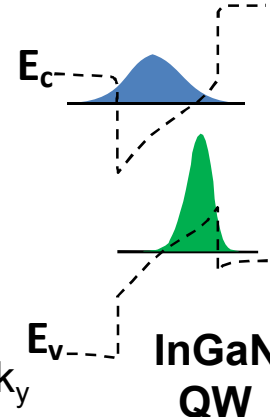
$$\left. \frac{\partial n_{\sigma, \alpha \sigma, k_{\perp}}}{\partial t} \right|_{col} = -\gamma_{c-c} [n_{\sigma, \alpha \sigma, k_{\perp}} - f_{\sigma, \alpha \sigma, k_{\perp}}(\mu_{\sigma}^p, T_p)] - \gamma_{c-p} [n_{\sigma, \alpha \sigma, k_{\perp}} - f_{\sigma, \alpha \sigma, k_{\perp}}(\mu_{\sigma}^l, T_l)]$$

→ Calculate radiative contribution directly  
→ avoids constant B parameter

Band-  
structure



Quantum –  
confinement &  
polarization fields



GaN  
barrier

InGaN  
QW

## "ABC model"

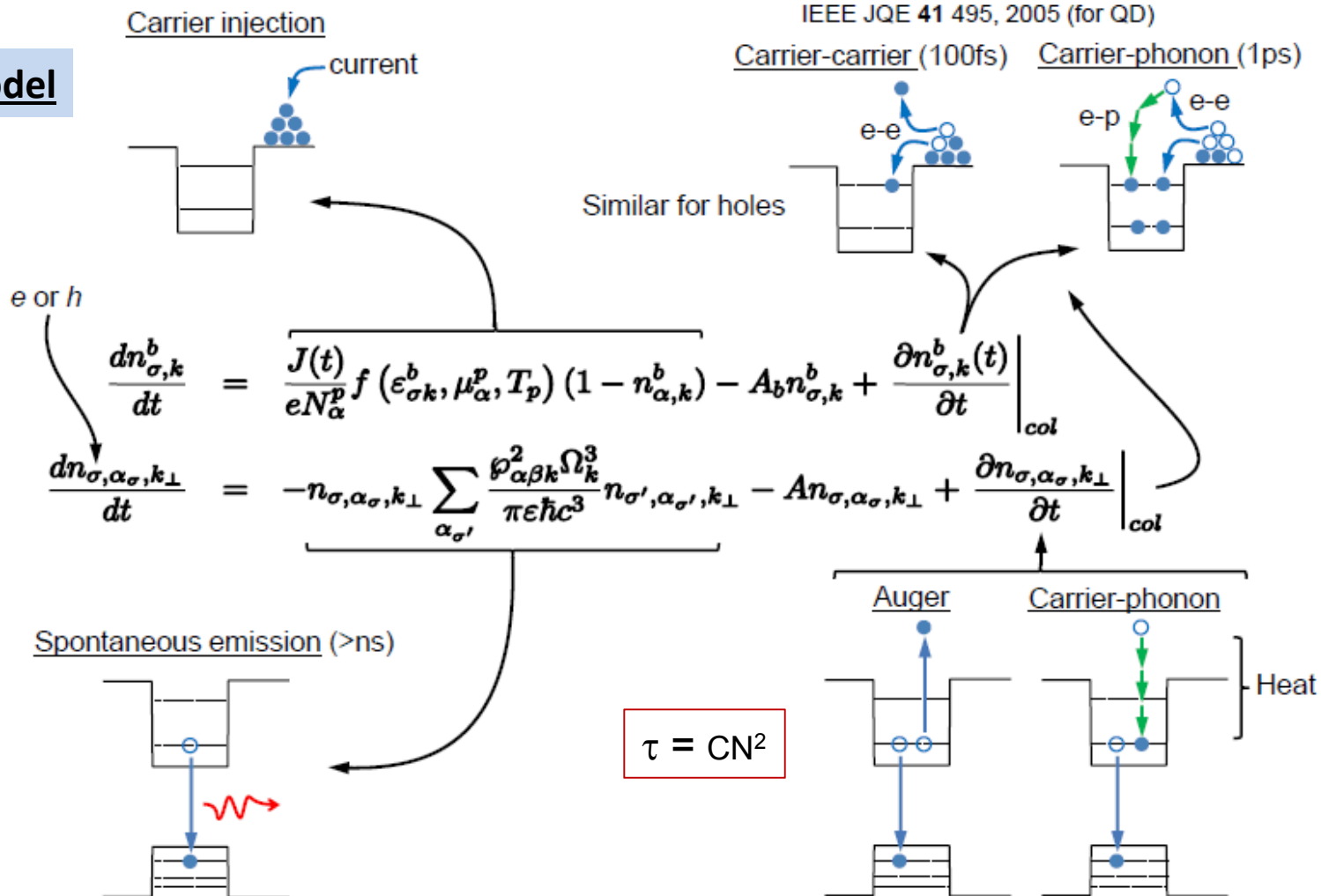
$$\frac{dN}{dt} = \frac{J}{ed} - \underset{\substack{\uparrow \\ \text{Defects}}}{AN} - \underset{\substack{\uparrow \\ \text{Spontaneous emission}}}{BN^2} - \underset{\substack{\uparrow \\ \text{Auger?}}}{CN^3}$$

# Summary of model and equations

## New Model

Barrier:

QW:



IEEE JQE 38 402, 2002 (for QW)

IEEE JQE 41 495, 2005 (for QD)

Carrier-carrier (100fs) Carrier-phonon (1ps)

Auger

Carrier-phonon

Heat

$$\tau = CN^2$$



SSLS  
EFRC

ICNS 2011

Chow et al, Appl. Phys. Lett. 97, 121105 (2010)

5



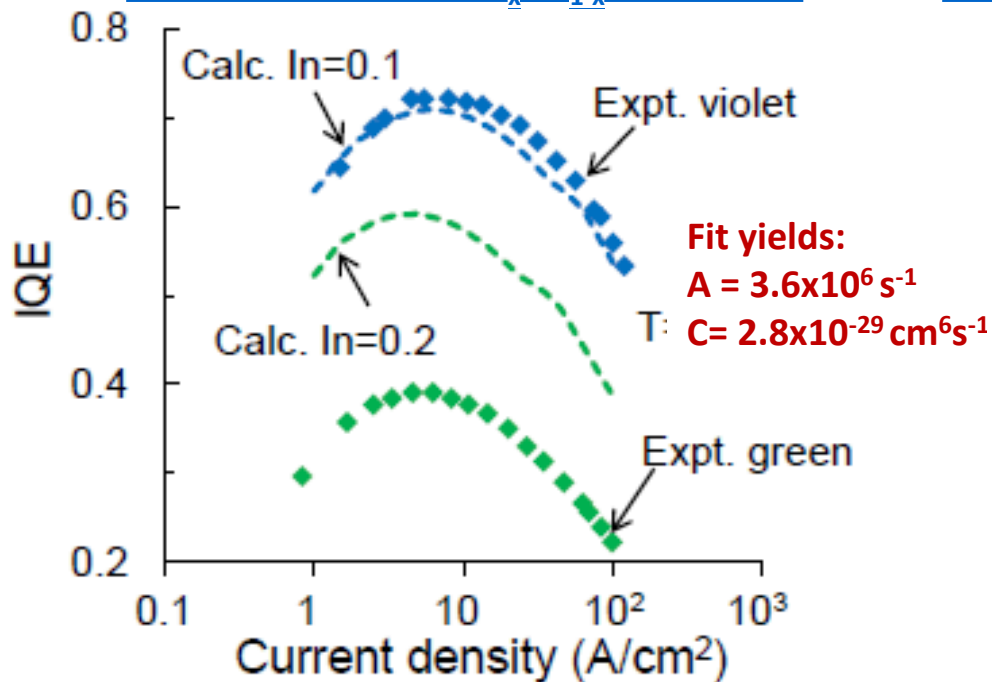
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Laboratories

# Contributions to LED Efficiency Dependence on Wavelength

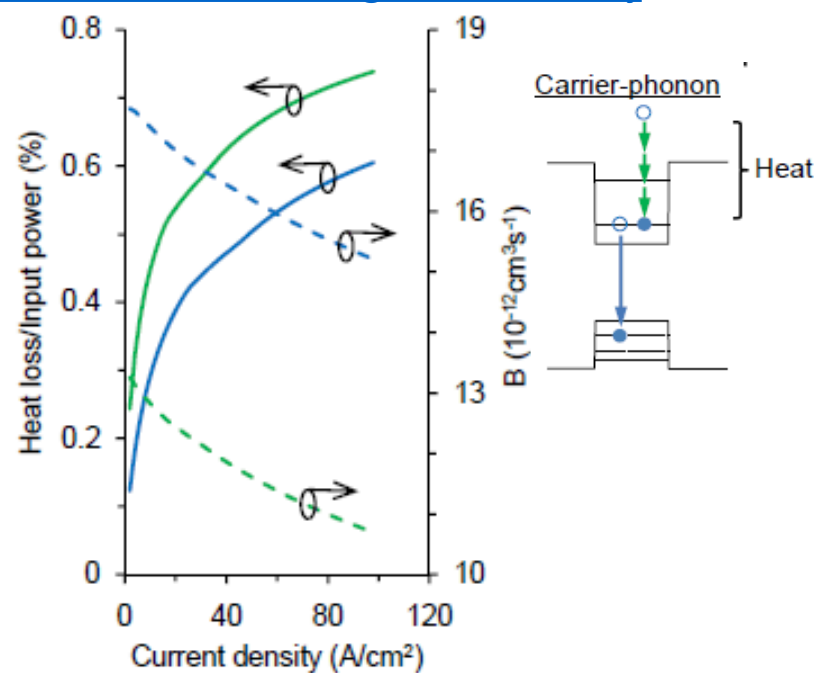
**Outstanding issue: why are longer wavelength (green) InGaN LEDs less efficient ?**

→ hypotheses: increased strain/polarization fields, increased non-radiative defects

IQE of Commercial  $\text{In}_x\text{Ga}_{1-x}\text{N}$  QW LEDs



Contributions to lower green efficiency



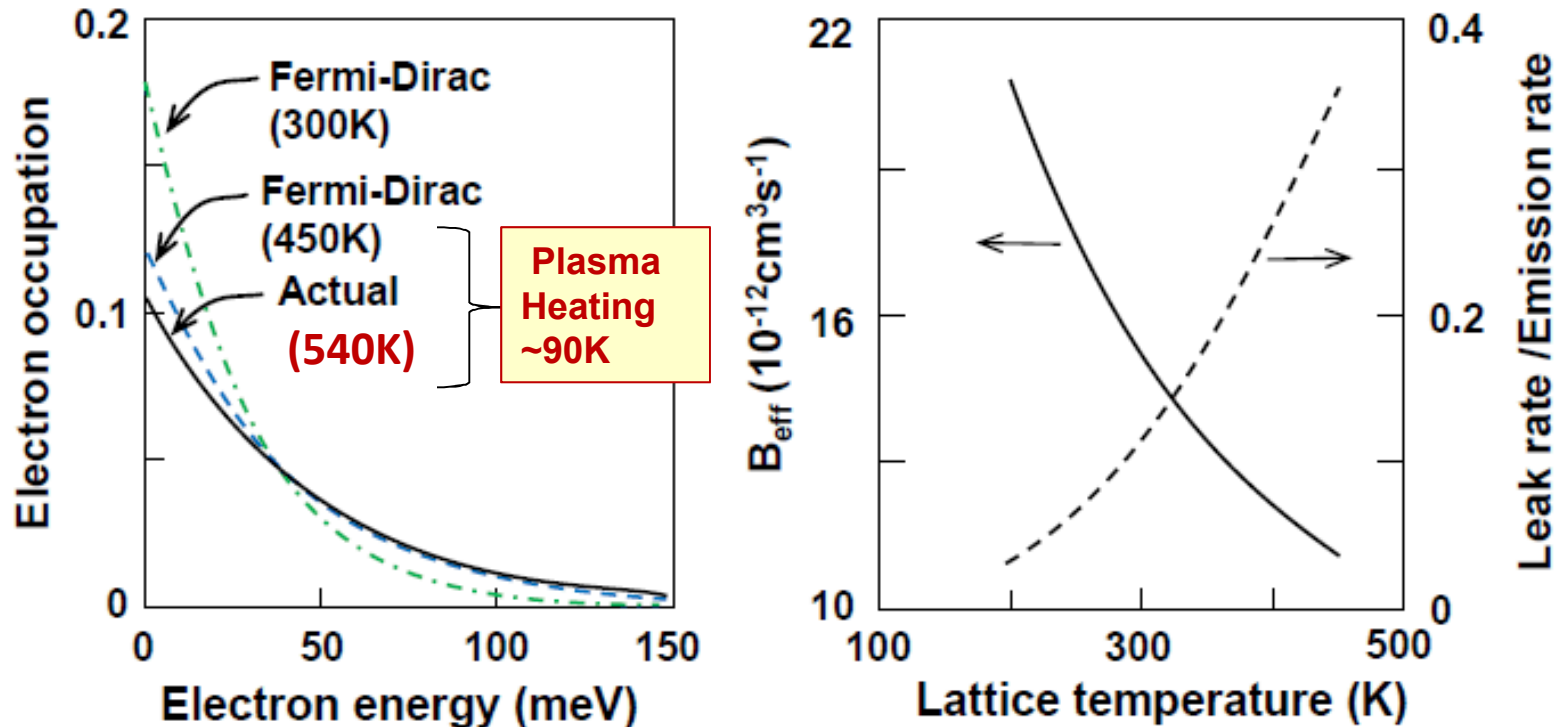
**Model insights: ~1/3 of difference between violet and green LED efficiency is due to intrinsic contributions**

→ **enhanced heat loss (phonons), reduced effective B coefficient**

$$B_{eff} = N \cdot 2 \sum_{k_{\perp}} |\phi_{k_{\perp}}|^2 \Omega_{k_{\perp}}^3 (\pi \epsilon \hbar c^3)^{-1} n_{e,k_{\perp}} n_{h,k_{\perp}}$$

# Contributions to LED Efficiency Dependence on Temperature

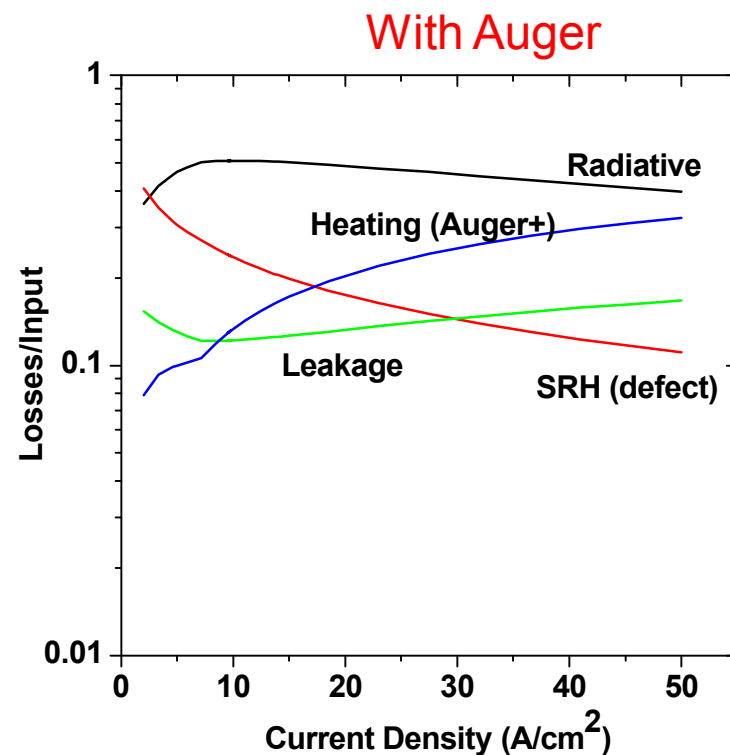
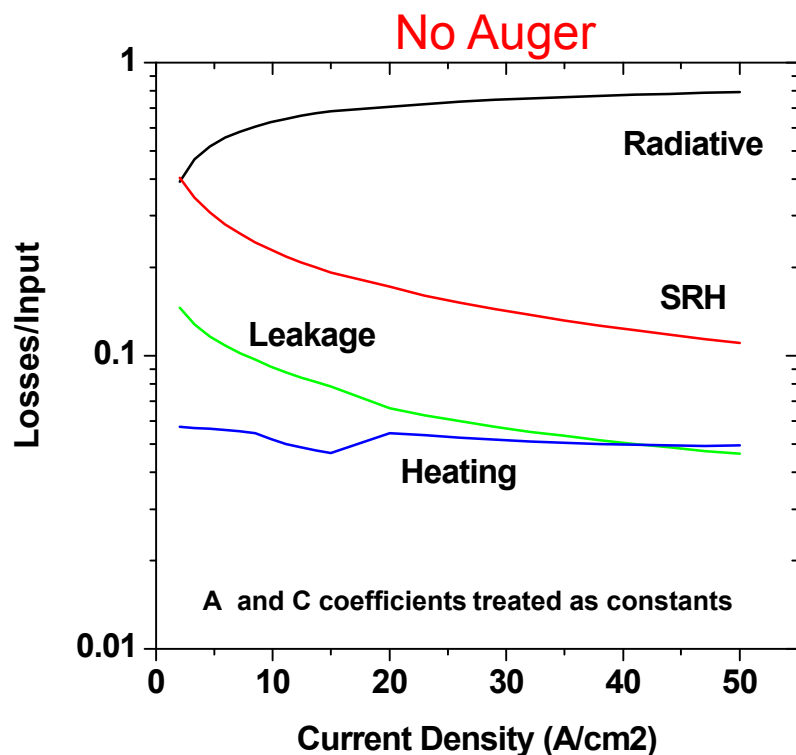
Assumptions:  $\text{In}_{0.1}\text{Ga}_{0.9}\text{N}$  QW LED (violet)  $J = 100 \text{ A/cm}^2$   $T = 450\text{K}$



- Model quantifies **plasma heating** at high current densities ( $100 \text{ A/cm}^2$ )
- Quantifies contributions to lower efficiency at elevated temperatures:  
→ **carrier leakage out of QWs, reduced  $B_{\text{eff}}$**

# Interdependences of Loss Contributions

$\text{In}_{0.1}\text{Ga}_{0.9}\text{N}$  QW



- For violet QWs, losses due to phonon emission (heating) is minimal up to 50 A/cm<sup>2</sup> in the absence of Auger recombination
- Auger-related heating drives enhanced carrier leakage



## II. Potential Role of Defects in Efficiency Droop

### LED rate-equation model

$$\frac{dN}{dt} = \frac{J}{ed} - \underbrace{AN}_{\substack{\text{Defects} \\ \uparrow}} - \underbrace{BN^2}_{\substack{\text{Spontaneous} \\ \text{emission} \\ \uparrow}} - \underbrace{CN^3}_{\substack{\text{Auger?} \\ \uparrow}}$$

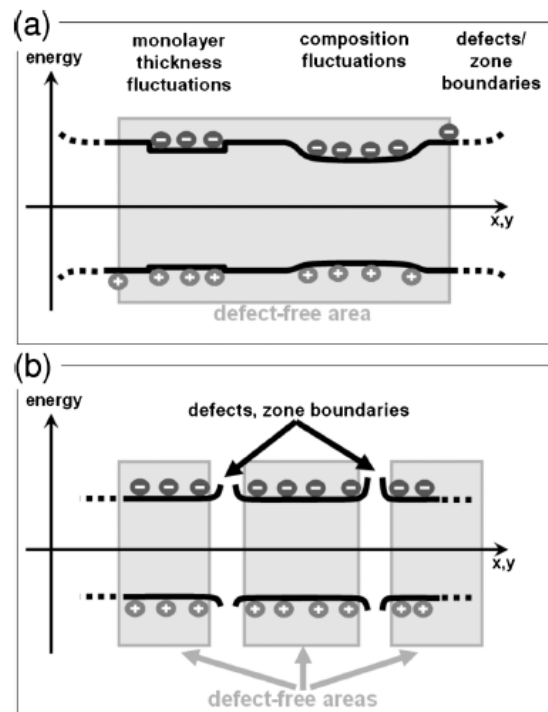
$$\text{Internal quantum efficiency} = \frac{BN^2}{AN + BN^2 + CN^3}$$

### Questions:

- Can defects contribute nonlinear terms in the absence of localization?
- What defect properties are required to impact efficiency in the droop regime?

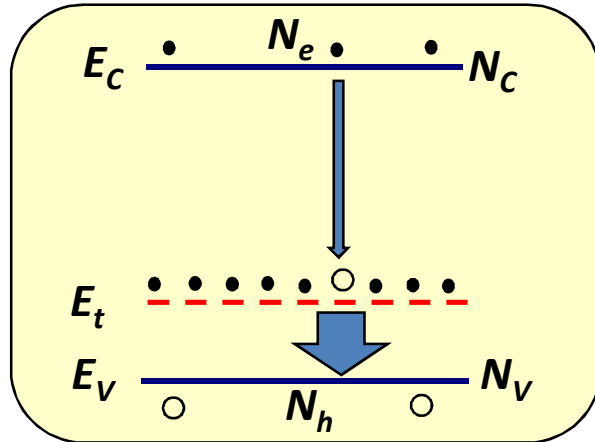
### Density-Activated Defect Recombination

$$J_{\text{DADR}} = \begin{cases} 0, & \text{for } N < N_0 \\ \frac{en_w}{\tau_{\text{DADR}}} \frac{(N - N_0)^2}{2N_0}, & \text{for } N > N_0 \end{cases}$$



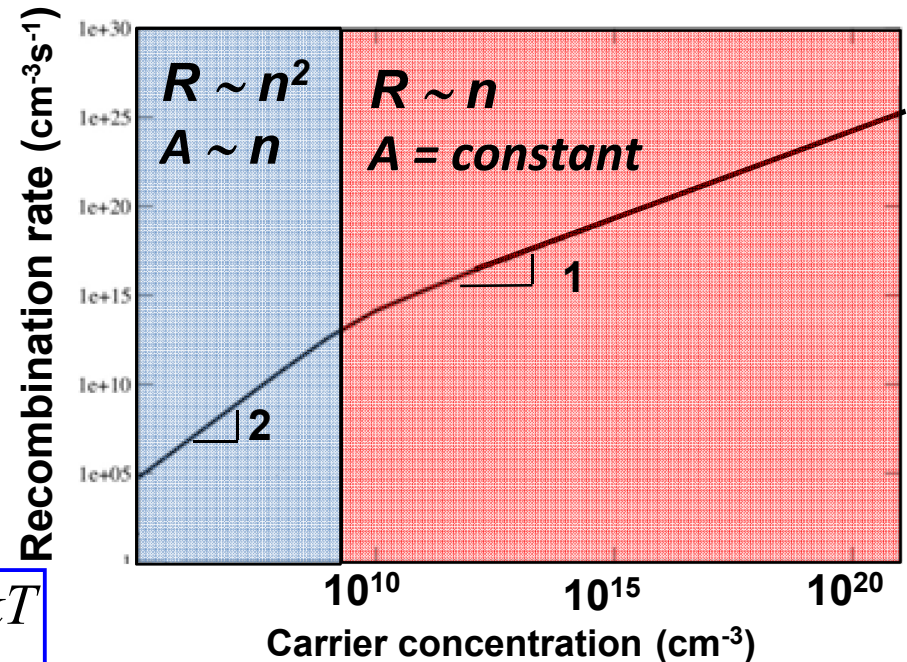
Hader et al., APL 2011

# Basic SRH Theory Predicts A(n)



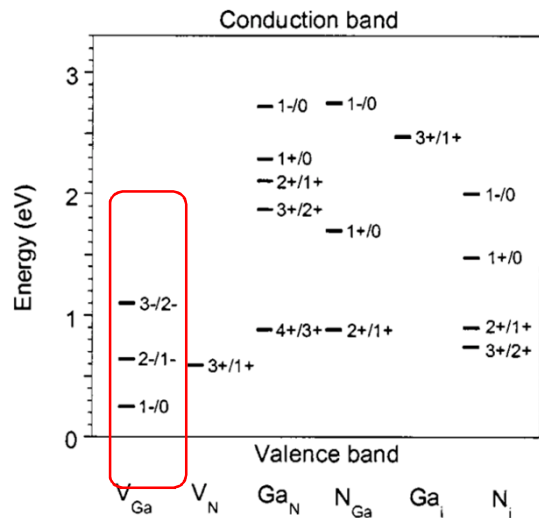
For  $N_e = N_h = n \ll N_v \exp(E_v - E_t)/kT$

$$R_{SRH} \approx \frac{n^2}{\tau_{n0} N_v \exp(E_v - E_t)/kT}$$



- $R \sim n^2$  when hole emission outpaces hole capture
- $A$  is not constant even for simple defects
- **BUT**, simple defects cannot explain droop

# What About Multilevel Defects?



$V_{Ga}$ -like test case:

$$N_{TOTAL} = 3 \times 10^{17}$$

$$E^{-3/2} = 1.00 \text{ eV}$$

$$E^{-2/-1} = 0.55 \text{ eV}$$

$$E^{-1/0} = 0.15 \text{ eV}$$

$$C_n^{-3/2} = 6.2e-13 \text{ cm}^3\text{s}^{-1}$$

$$C_n^{-2/-1} = 1.3e-11 \text{ cm}^3\text{s}^{-1}$$

$$C_n^{-1/0} = 3.0e-10 \text{ cm}^3\text{s}^{-1}$$

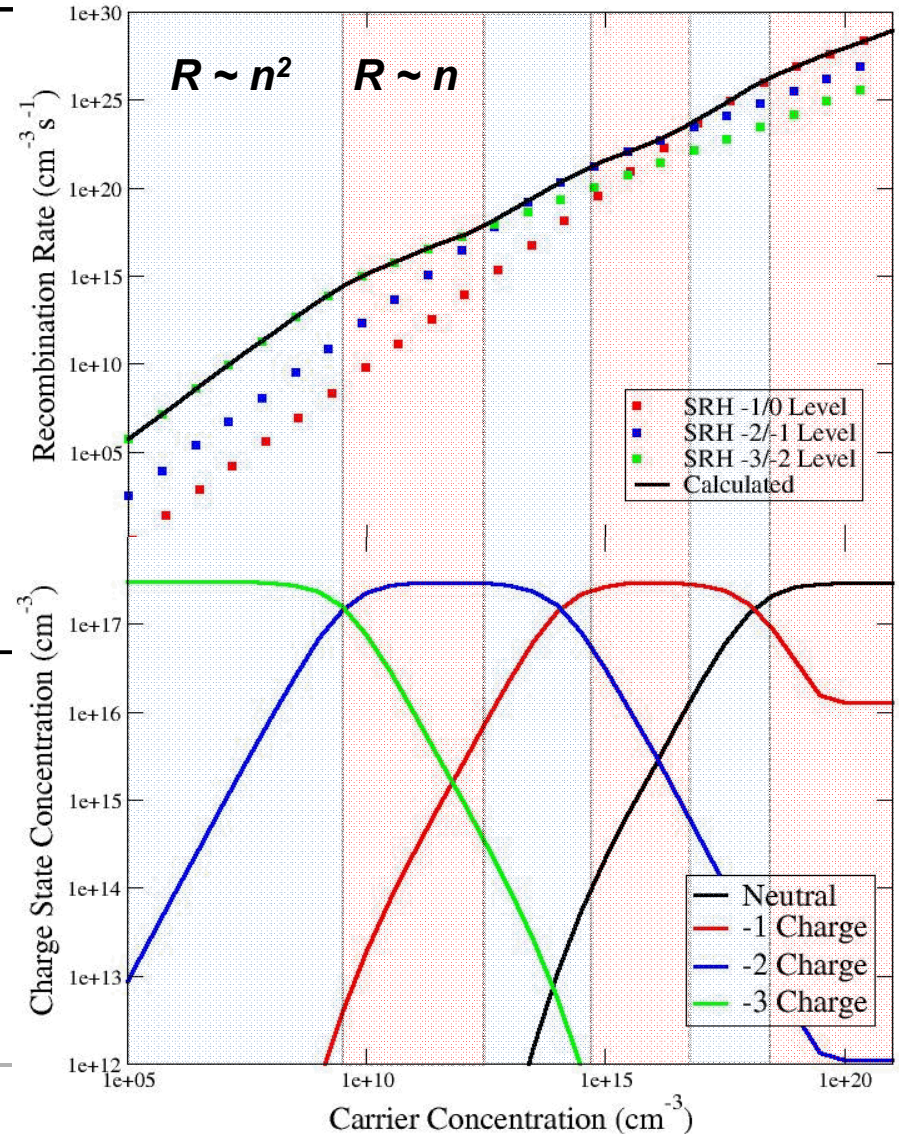
$$C_p^{-1/0} = 6.7e-9 \text{ cm}^3\text{s}^{-1}$$

$$C_p^{-2/-1} = 1.5e-7 \text{ cm}^3\text{s}^{-1}$$

$$C_p^{-3/2} = 3.3e-6 \text{ cm}^3\text{s}^{-1}$$

Limpijumong and Van de Walle, PRB 2004.

## Calculated $R(n)$

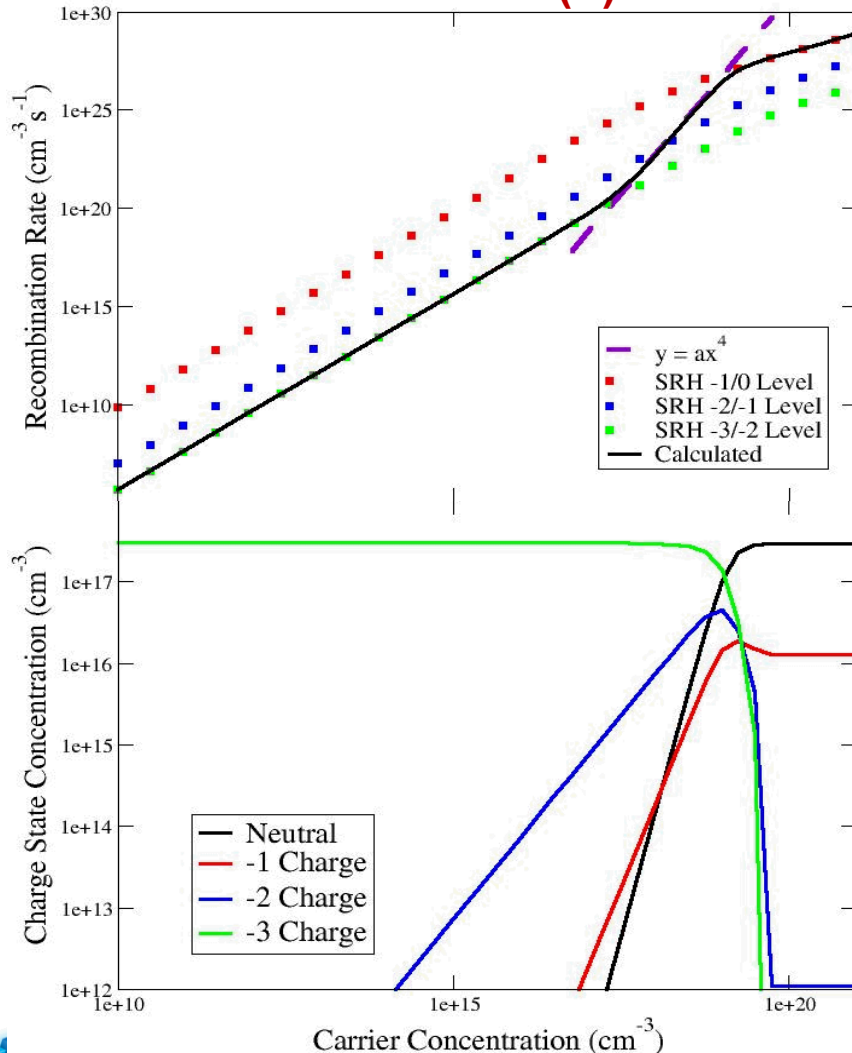


- Multiple  $R \sim n^2$  regimes
  - Summing SRH rates gives decent approximation
  - **Shallower levels** have  $n^2$  to  $n$  cross-over at larger  $n$
- ➔ **Still not  $R \sim n^2$**

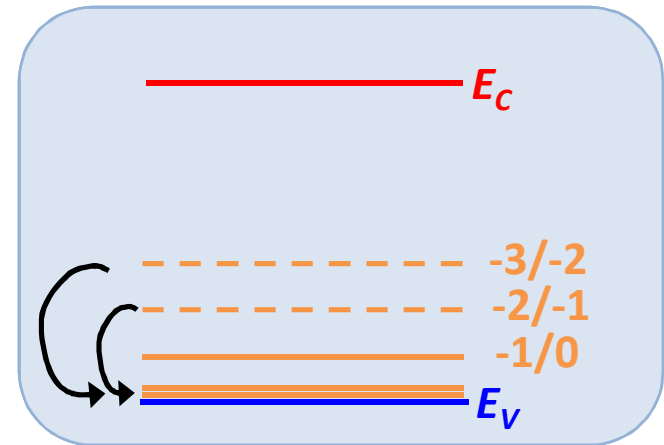


# What About Negative-U Defects?

## Calculated $R(n)$



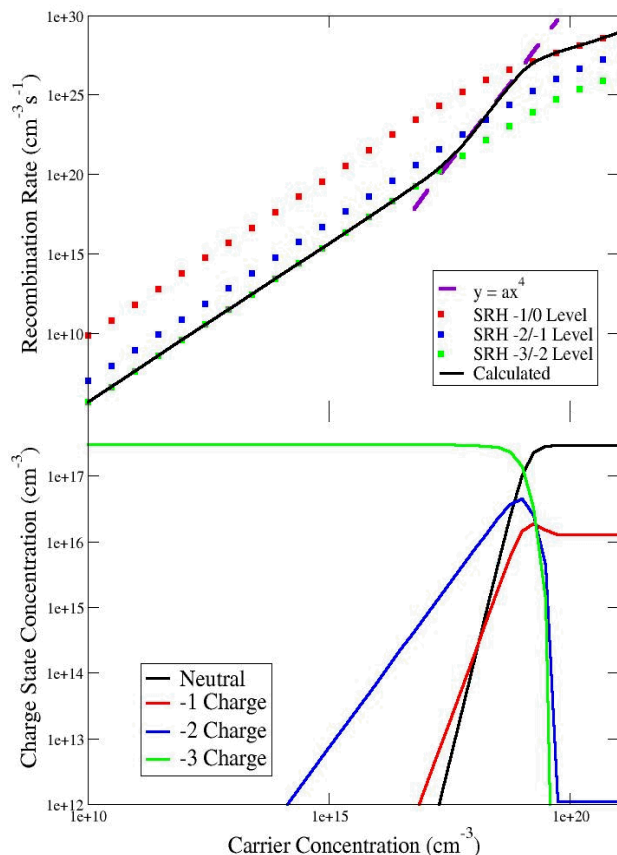
## Defect Energy Levels



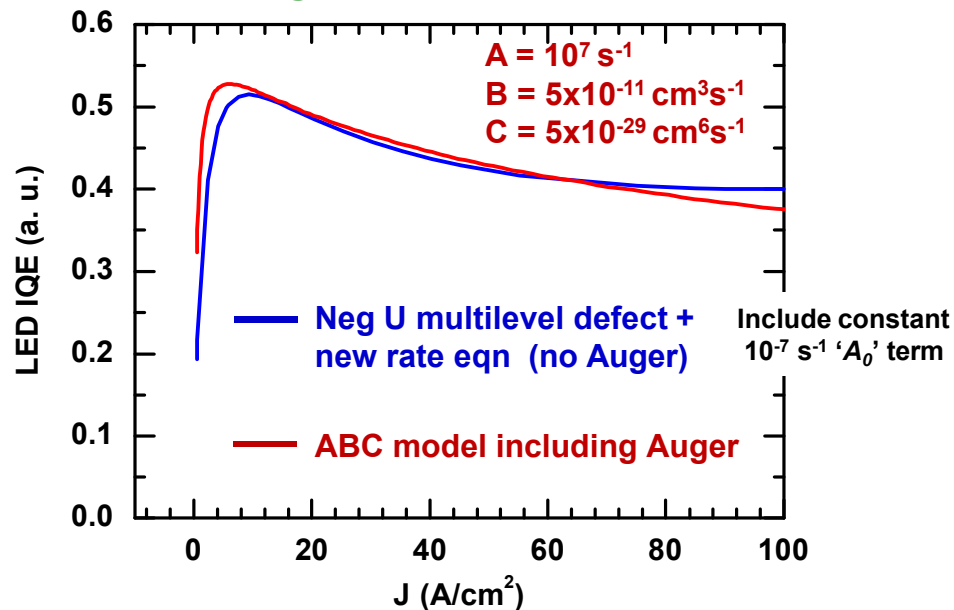
- **-U behavior** makes the -2 and -1 charge states unstable
- **Shallow levels** keep defect in -3 state until  $10^{18} - 10^{19} \text{ cm}^{-3}$  carriers
- Defect recombination requires  **$3h^+ + e^-$**  giving  **$R \sim n^4$**
- ➔ **Combined conditions sufficient to contribute in the droop regime**

# Influence of $A(n)$ on LED IQE

## Calculated $R(n)$ --Negative U defect



## Comparing two models for LED IQE



- Multilevel defect can contribute to droop, given:
  - **Negative-U defect**
  - **Sufficiently shallow defect level**
- **Auger or other  $n^2$  mechanism still required** at highest currents to match experiments



# Summary

- Modified rate equation model enables insights into contributions to reduced LED efficiency up to high carrier densities; impact of bandstructure and plasma heating on:
  - LED efficiency versus wavelength
  - LED efficiency at elevated temperatures
  - Impact of Auger on other loss terms, including radiative recombination and leakage
- Explored conditions for non-linear loss via recombination at defects without invoking carrier localization
  - multi-level defect with negative U behavior,  $V_{Ga}$ -like defect,  $R \sim n^4$
  - Shallow defect to delay nonlinear contribution to high carrier densities ( $1e18-1e19 \text{ cm}^{-3}$ )
  - may contribute to higher order coefficients

*LED Chip*



*Packaged LED*



*Luminaires*



*Exterior hanging light*



*Exterior porch light*



*Track light*



*Interior recessed can*

Figures from DOE EERE SSL MYPP March 2010